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Image Processing: Machine Vision Applications V

Philip R. Bingham
Edmund Y. Lam
Editors

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Contents

vii *Conference Committee*

SESSION 1 SYSTEMS

- 8300 03 **Sensor placement optimization in buildings** [8300-02]
S. Bianco, F. Tisato, Univ. degli Studi di Milano-Bicocca (Italy)
- 8300 04 **Optical feature extraction with illumination-encoded linear functions** [8300-03]
R. Gruna, Karlsruher Institut für Technologie (Germany); J. Beyerer, Fraunhofer-Institut für Optronik, Systemtechnik und Bildauswertung (Germany)

SESSION 2 ALGORITHMS

- 8300 05 **An illumination-invariant phase-shifting algorithm for three-dimensional profilometry** [8300-04]
F. Deng, The Univ. of Hong Kong (Hong Kong, China) and ASM Assembly Automation Ltd. (Hong Kong, China); C. Liu, W. Sze, J. Deng, K. S. M. Fung, W. H. Leung, ASM Assembly Automation Ltd. (Hong Kong, China); E. Y. Lam, The Univ. of Hong Kong (Hong Kong, China)
- 8300 06 **Fusing shape and texture features for pose-robust face recognition** [8300-05]
T. Gernoth, R.-R. Grigat, Technische Univ. Hamburg-Harburg (Germany)
- 8300 07 **Automated inspection of tubular material based on magnetic particle inspection** [8300-06]
A. Mahendra, Lab. d'Electronique, d'Informatique et d'Image, CNRS, Univ. de Bourgogne (France) and Vallourec S.A. (France); C. Stolz, F. Meriaudeau, Lab. d'Electronique, d'Informatique et d'Image, CNRS, Univ. de Bourgogne (France); S. Petit, A. Noel, F. Degoutin, Vallourec S.A. (France)

SESSION 3 DETECTION AND TRACKING

- 8300 09 **Runway hazard detection in poor visibility conditions** [8300-08]
B. Jiang, National Institute of Aerospace (United States); Z. Rahman, Old Dominion Univ. (United States)
- 8300 0A **Application of image processing to track twin boundary motion in magnetic shape memory alloys** [8300-09]
A. Rothenbuhler, E. H. Barney Smith, P. Müllner, Boise State Univ. (United States)
- 8300 0B **A new point process model for trajectory-based events annotation** [8300-10]
N. Ballas, CEA LIST (France) and Mines ParisTech (France); B. Delezoide, CEA LIST (France); F. Prêteux, Mines ParisTech (France)
- 8300 0C **Face detection and eyeglasses detection for thermal face recognition** [8300-11]
Y. Zheng, Alcorn State Univ. (United States)

SESSION 4 APPLICATIONS

- 8300 OD **Strain analysis by regularized non-rigid registration** [8300-25]
A. Badshah, P. O'Leary, M. Harker, Montan Univ. Leoben (Austria); D. Tscharnuter, Polymer Competence Ctr. Leoben GmbH (Austria)
- 8300 OE **Combining spatial and spectral information to improve crop/weed discrimination algorithms** [8300-12]
L. Yan, G. Jones, S. Villette, J. N. Paoli, C. Gée, AgroSup Dijon (France)
- 8300 OF **Automated parasites detection in clams by transillumination imaging and pattern classification** [8300-13]
M. Soto, P. Coelho, J. Soto, S. Torres, D. Sbarbaro, Univ. de Concepción (Chile)
- 8300 OG **Vision-based in-line fabric defect detection using yarn-specific shape features** [8300-14]
D. Schneider, T. Aach, RWTH Aachen (Germany)
- 8300 OH **3D temperature mapping of turboshaft components using thermal paints and color recognition** [8300-15]
S. Guérin, ONERA (France) and Turbomeca SA (France); C. Lempereur, ONERA (France); P. Brevet, Turbomeca SA (France)

INTERACTIVE PAPER SESSION

- 8300 OI **Efficient local approximation of perceptual color differences for color inspection** [8300-16]
R. Huber-Mörk, Austrian Institute of Technology (Austria)
- 8300 OJ **Modified fuzzy c-means applied to a Bragg grating-based spectral imager for material clustering** [8300-17]
A. Rodríguez, J. L. Nieves, E. Valero, Univ. de Granada (Spain); E. Garrote, TECNALIA (Spain); J. Hernández-Andrés, J. Romero, Univ. de Granada (Spain)
- 8300 OK **Robust recognition of 1D barcodes using Hough transform** [8300-18]
J. Dwinell, SICK, Inc. (United States); P. Bian, Microsoft Corp. (China); L. X. Bian, SICK, Inc. (United States)
- 8300 OL **Estimating the coordinates of pillars and posts in the parking lots for intelligent parking assist system** [8300-19]
J. H. Choi, J. G. Kuk, Seoul National Univ. (Korea, Republic of); Y. I. Kim, Mando Corp. (Korea, Republic of); N. I. Cho, Seoul National Univ. (Korea, Republic of)
- 8300 OM **Recognizing human gestures using a novel SVM tree** [8300-21]
H. Jain, A. Chatterjee, S. Kumar, B. Raman, Indian Institute of Technology Roorkee (India)
- 8300 ON **Fabric defect detection using the wavelet transform in an ARM processor** [8300-22]
J. A. Fernández, Antonio Nariño Univ. (Colombia); S. A. Orjuela, Univ. Gent (Belgium); J. Álvarez, Antonio Nariño Univ. (Colombia); W. Philips, Univ. Gent (Belgium)

8300 00

Orthophotoplan segmentation based on region merging for roof detection [8300-23]

Y. El Merabet, Univ. de Technologie de Belfort-Montbéliard (France) and Univ. Ibn Tofail (Morocco); C. Meurie, Y. Ruichek, Univ. de Technologie de Belfort-Montbéliard (France); A. Sbihi, Univ. Abdelmalek Essadi (Morocco); R. Touahni, Univ. Ibn Tofail (Morocco)

Author Index

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 Edmund Y. Lam, The University of Hong Kong (Hong Kong, China)

- 2 Algorithms
Philip R. Bingham, Oak Ridge National Laboratory (United States)
- 3 Detection and Tracking
David Fofi, Université de Bourgogne (France)
- 4 Applications
Kurt S. Niel, Fachhochschule Wels (Austria)